

**Notice of References Cited**

Application/Control No.

09/837,480

Applicant(s)/Patent Under

Reexamination

NAKATA ET AL.

Examiner

Tracy Dove

Art Unit

1745

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	B.C. Cullity, Elements of X-Ray Diffraction, 2 <sup>nd</sup> edition, pages 281-282. 1978 (no month)			
	V				
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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